## **Power MOSFET** 100 V, 8 m $\Omega$ , 104 A, Single N–Channel

#### Features

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS (T <sub>J</sub> = 25°C unless otherw Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V <sub>DSS</sub>	100	V
Gate-to-Source Voltage			V <sub>GS</sub>	±20	V
Continuous Drain		$T_C = 25^{\circ}C$	I <sub>D</sub>	104	Α
Current $R_{\theta JC}$ (Notes 1, 2, 3)	Steady	T <sub>C</sub> = 100°C		66	
Power Dissipation	State	$T_C = 25^{\circ}C$	PD	138	W
$R_{\theta JC}$ (Notes 1, 2)		T <sub>C</sub> = 100°C		56	1
Continuous Drain Current $R_{\theta JA}$ (Notes 1, 2, 3)	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	16	А
		$T_A = 100^{\circ}C$		10	
Power Dissipation		$T_A = 25^{\circ}C$	PD	3.3	W
$R_{\theta JA}$ (Notes 1 & 2)		$T_A = 100^{\circ}C$		1.3	1
Pulsed Drain Current	T <sub>A</sub> = 25	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	370	А
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to + 150	°C
Source Current (Body Diode)			۱ <sub>S</sub>	130	А
Single Pulse Drain–to–Source Avalanche Energy (I <sub>L(pk)</sub> = 50 A)			E <sub>AS</sub>	125	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			ΤL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{ extsf{ heta}JC}$	0.9	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	39	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.

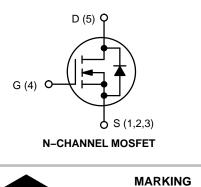
3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

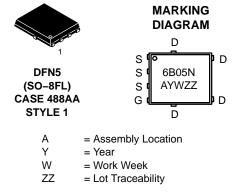


#### **ON Semiconductor®**

#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
100 V	8 mΩ @ 10 V	104 A





#### **ORDERING INFORMATION**

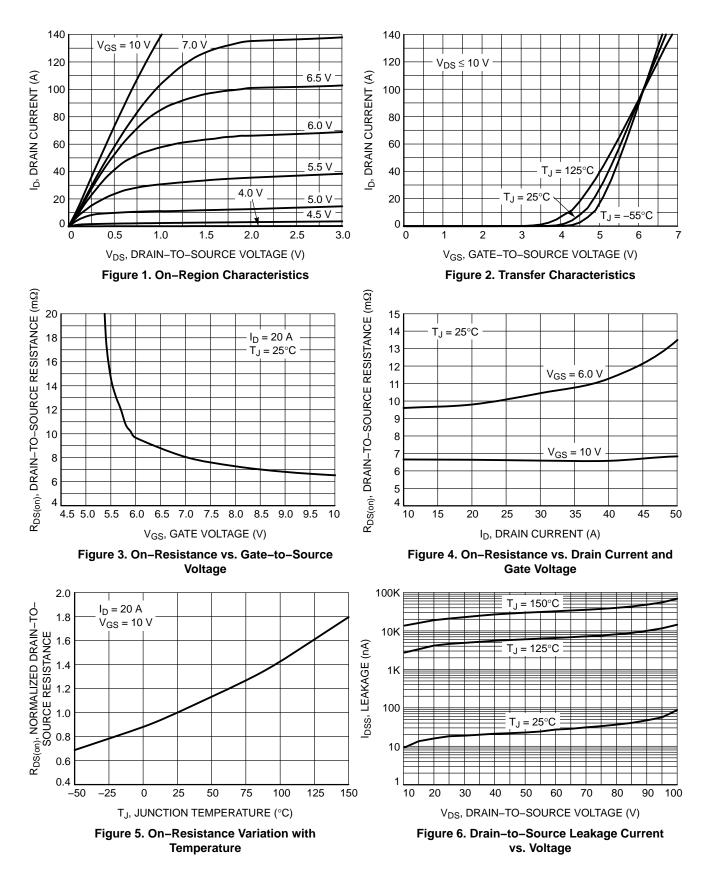
See detailed ordering, marking and shipping information on page 5 of this data sheet.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS}$ = 0 V, $I_D$ = 250 $\mu$ A		100			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				73		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V,$	T <sub>J</sub> = 25 °C			10	
		V <sub>DS</sub> = 80 V	T <sub>J</sub> = 125°C			100	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA
ON CHARACTERISTICS (Note 4)	-					-	
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 250 μA	2.0		4.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-7.9		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 V$	I <sub>D</sub> = 20 A		6.5	8.0	mΩ
		$V_{GS} = 6.0 V$	I <sub>D</sub> = 10 A		9.6	14	
CHARGES, CAPACITANCES & GATE RE	SISTANCE						
Input Capacitance	C <sub>ISS</sub>			3100		pF	
Output Capacitance	C <sub>OSS</sub>	$V_{GS}$ = 0 V, f = 1 MHz, $V_{DS}$ = 50 V			570		
Reverse Transfer Capacitance	C <sub>RSS</sub>				28		
Total Gate Charge	Q <sub>G(TOT)</sub>				44		1
Threshold Gate Charge	Q <sub>G(TH)</sub>				5.0		1
Gate-to-Source Charge	Q <sub>GS</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 50 V; $I_{D}$ = 25 A $T_{J}$ = 25 °C			14		- nC
Gate-to-Drain Charge	Q <sub>GD</sub>				12		
Plateau Voltage	V <sub>GP</sub>				5.0		V
Gate Resistance	R <sub>G</sub>				1.0		Ω
SWITCHING CHARACTERISTICS (Note &	5)						
Turn–On Delay Time	t <sub>d(ON)</sub>				14		
Rise Time	tr	$\label{eq:VGS} \begin{array}{l} V_{GS} = 10 \; V, \; V_{DS} = 50 \; V, \\ I_{D} = 25 \; A, \; R_{G} = 1.0 \; \Omega \end{array}$			43		ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>				39		
Fall Time	t <sub>f</sub>				16		
DRAIN-SOURCE DIODE CHARACTERIS	TICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	$T_J = 25^{\circ}C$		0.9	1.2	
		$I_{\rm S} = 25 \rm{A}$ $T_{\rm J} = 125^{\circ}\rm{C}$			0.8		V
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dI <sub>S</sub> /d <sub>t</sub> = 100 A/µs, I <sub>S</sub> = 25 A			58		
Charge Time	ta				30		ns
Discharge Time	t <sub>b</sub>				28		1
Reverse Recovery Charge	Q <sub>RR</sub>				83		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
4. Pulse Test: pulse width ≤ 300 µs, duty cycle ≤ 2%.
5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**



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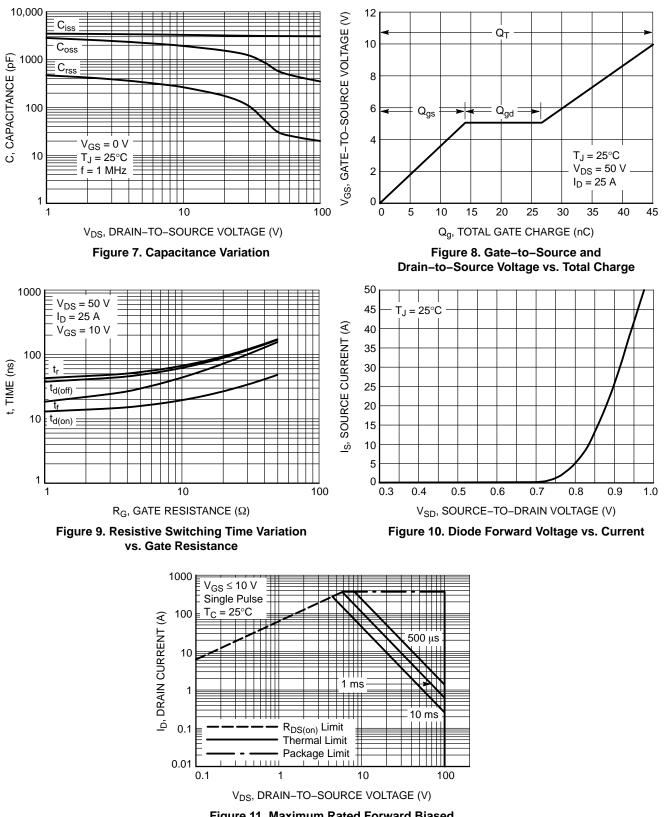
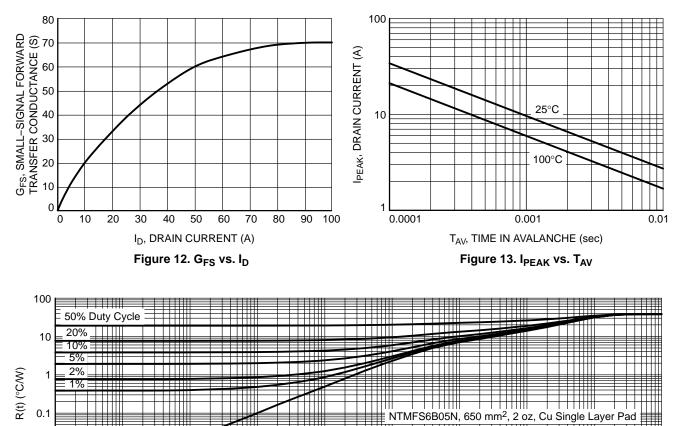


Figure 11. Maximum Rated Forward Biased Safe Operating Area

#### **TYPICAL CHARACTERISTICS**

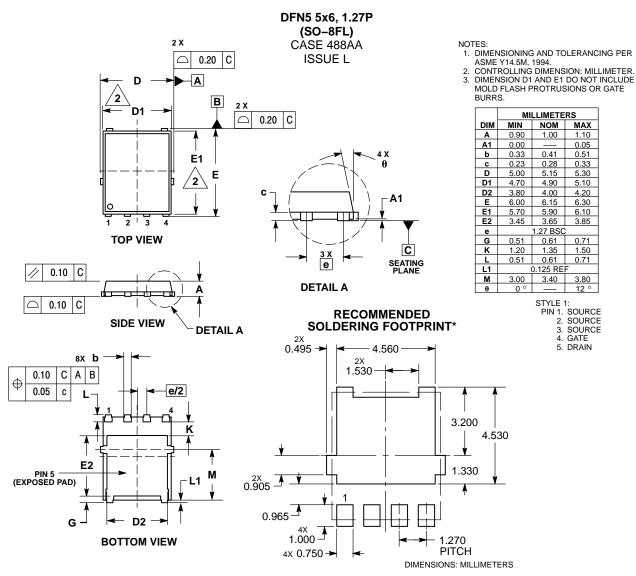


0.01 Single Pulse					
0.001 0.00001 0.00001 0.00	01 0.001 0.01	0.1 1	10	100	1000
	PULSE TI	ME (sec)			
	Figure 14. Ther	mal Response			
DEVICE ORDERING INFORMA	TION				
Device	Marking	Package		Shipping <sup>†</sup>	
	CDOEN	DENE	4	FOO / Tama & D	

Device	Marking	Package	Shipping <sup>†</sup>
NTMFS6B05NT1G	6B05N	DFN5 (Pb–Free)	1500 / Tape & Reel
NTMFS6B05NT3G	6B05N	DFN5 (Pb–Free)	5000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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